

**Notice of References Cited**

Application/Control No.

09/406,663

Applicant(s)/Patent Under  
Reexamination  
KNEBEL ET AL.

Examiner

Fred Ferris

Art Unit

2123

Page 1 of 2

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,528,156	06-1996	Ueda et al.	324/751
	B	US-6,483,327	11-2002	Bruce et al.	324/752
	C	US-5,251,159	10-1993	Rowson, James A.	703/14
	D	US-5,555,201	09-1996	Dangelo et al.	716/1
	E	US-5,270,643	12-1993	Richardson et al.	324/751
	F	US-5,539,652	07-1996	Tegethoff, Mauro V.	703/14
	G	US-6,342,701	01-2002	Kash, Jeffrey A.	250/458.1
	H	US-6,442,720	08-2002	Koprowski et al.	714/726
	I	US-5,940,545	08-1999	Kash et al.	382/312
	J	US-4,675,832	06-1987	Robinson et al.	345/441
	K	US-5,164,666	11-1992	Wolfgang et al.	324/751
	L	US-6,327,394	12-2001	Kash et al.	382/280
	M	US-4,763,288	08-1988	Deering et al.	703/19

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Diagnosis and Characterization of Timing-Related Defects by Time-Dependent Light Emission", D. Knebel et al, International Test Conference, IEEE, October 1998
	V	"Failure Analysis of ULSI circuits Using Photon Emission", Y. Uraoka, IEEE Log Number 9211664, IEEE 1993
	W	"The Attack of the "Holey Shmoos": A Case Study of Advanced DFD and Picosecond Imaging Circuit Analysis (PICA)", W. Huott, ITC International Test Conference, IEEE, January 1999
	X	"An Integrated Photon Emission Microscope and MOSFET Characterization System of Combined Microscopic and Macroscopic Device Analysis", T.H. Ng, IEEE Proceedings for 7 <sup>th</sup> IPFA '99, August 1999

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

**Notic of References Cited**

Application/Control No.

09/406,663

Applicant(s)/Patent Under  
Reexamination  
KNEBEL ET AL.

Examiner

Fred Ferris

Art Unit

2123

Page 2 of 2

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,172,512	01-2001	Evans et al.	324/752
	B	US-6,128,768	10-2000	Ho, William Wai Yan	716/5
	C	US-6,263,301	07-2001	Cox et al.	703/14
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"New Failure Analysis of ULSI circuits Using Photon Emission", Y. Uraoka, Proc. IEEE 1992 Int. Conference on Microelctronis Test Structures, Vol 5, March 1992
	V	"Picosecond Imaging Circuit Analysis of the POWER3 Clock Distribution", P.N. Sandra, 1999 IEEE International Solid-State Conference, June 1999.
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.